Figures:

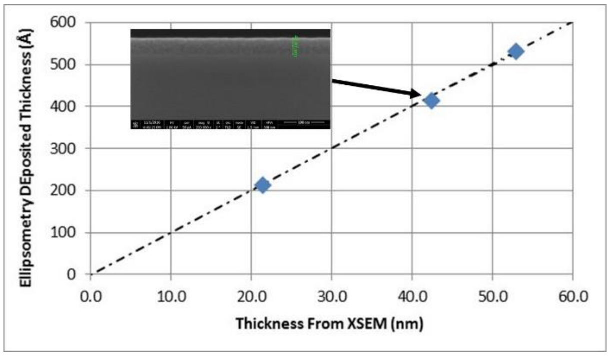

Figure 1: Comparison of deposited thickness to xSEM measurements. Long process times were used to improve the relative accuracy of the SEM measurements.

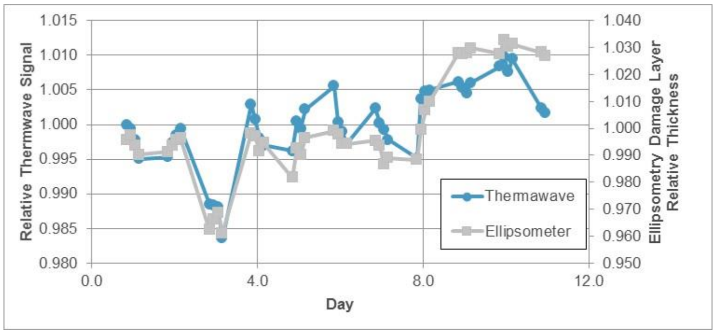

Figure 2: Marathon results over 12 days showing ellipsometry thickness of damage layer tracks with Thermawave

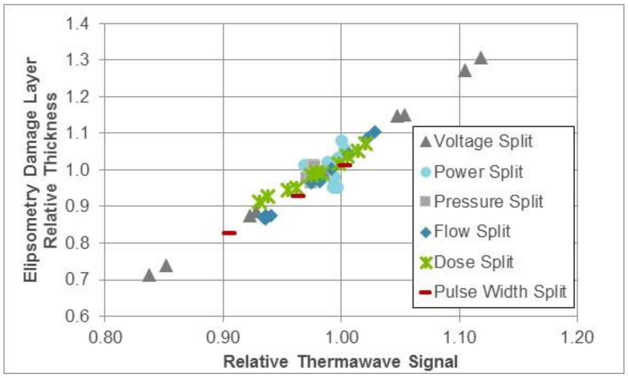

Figure 3: Correlation of Thermawave with ellipsometry damage thickness as a variety of process parameters are varied.